PCN Num	ber:	201808)180829000.1 <mark>.B</mark>			PCN Date: Dec 13, 2018			
Title: Qualification of TSMC-WFT as an additional Wafer Fab Site option for select devices									
Customer Contact:			PCN Manager Der		ot:	Quality Services		ity Services	
Proposed 1 st Ship Date:		Nov	Nov 29, 2018 Estima Availab		_			provided at ole request.	
Change Type:									
Assembly Site			Assembly Process				Assembly Materials		
Desig			Electrical Spe]			ical Specification	
Test S				ping/Labeling				Test Process	
	Bump Site		Wafer Bump					Wafer Bump Process	
⊠ Wafer	Fab Site		Wafer Fab Ma		[Wafer F	ab Process	
Part number change									
			PCN	Details					
Description	on of Change								
Revision B is to announce the <u>addition</u> of new devices that were not included on the original PCN notification. These new devices are highlighted in bold in the device list below. The expected first shipment date for these new devices specifically, will be 90 days from this notice (March 13, 2019). The proposed 1 st ship date of Nov 29, 2018 still applies for the original set of devices. Texas Instruments is pleased to announce the qualification of its TSMC-WFT fabrication facility as an additional Wafer Fab source for the selected devices listed in "Product Affected" section.									
	Curren	t Sites			Ad	Additional Sites			
Curren Fab Sit	_	cess	Wafer Diameter	Additional Fab Site		Pı	ocess	Wafer Diameter	
AMS	MIXEDS	IG-0 35	200mm	TSMC-WFT	M	IXFI	OSIG-0.3		
71113	THALDS	10 0.55	20011111	13/16 11/1	1		2010 013	20011111	
In addition	, the datashee	+ nn.h.a	ممحمل النبيير	ina					
Device F	<u> </u>	<u>t numbe</u>					Cha	inge To:	
CC1020	ammy		Change From: SWRS046H						
CC1021			SWRS045E				35U4b1		
The CC1020 product datasheet is updated as seen in the change revision history below: CC1020 SWRS046I - NOVEMBER 2006 - REVISED SEPTEMBER 2018 www.tl.com								RS046I RS045F	
CC1020 SWRS046I - NOV	'EMBER 2006-REVISED		updated as se		e rev	isio	SWI n history	below: XAS STRUMENTS	
CC1020 SWRS0461-NOV	EMBER 2006-REVISED	SEPTEMBER	updated as se		e rev	isio	SWI n history	below: XAS STRUMENTS www.tl.com	
CC1020 SWRS046I-NOV 2 Revision	TEMBER 2006–REVISED On History on Revision H (Marc	SEPTEMBER	updated as se	en in the change			n history	below: XAS STRUMENTS www.tl.com	
CC1020 SWRS046I-NOV 2 Revision Changes from Globa	EMBER 2006-REVISED On History n Revision H (Marc	SEPTEMBER ch 2015) to	updated as se				n history	below: XAS STRUMENTS www.tl.com Page	
CC1020 SWRS046I-NOV 2 Revision Changes from Globa Globa	on History Revision H (Marc Changed upper fre	september ch 2015) to equency from	updated as se 2018 Revision I n 960 MHz to 930 M STD-T96	en in the change			n history	below: XAS STRUMENTS www.tl.com Page	
CC1020 SWRS046I-NOV 2 Revision Changes from Globa Globa These char	on History n Revision H (Marc Changed upper free: Removed reference nges may be v	ch 2015) to equency from es to ARIB	updated as se	en in the change	 link/	/cc1	n history Tello	below: XAS ISTRUMENTS WWW.tl.com Page	
CC1020 SWRS046I-NOV 2 Revision Changes from Globa Globa These char The CC102	on History m Revision H (Marc : Changed upper fre : Removed reference nges may be v	ch 2015) to equency from es to ARIB	updated as se	en in the change	llink,	/cc1	n history 020.pdf n history	below: XAS ISTRUMENTS WWW.tl.com Page	
CC1020 SWRS0461-NOV 2 Revision Changes from Globa Globa These chart The CC102 TEXAS INSTE	on History n Revision H (Marc Changed upper free: Removed reference nges may be v 1 product data UMENTS n August 20, 2016	ch 2015) to equency from es to ARIB a sheet is	updated as se	en in the change	llink/	isio	n history 020.pdf n history	Page CC1021 NOVEMBER 2018 Page	

These changes may be viewed at: http://www.ti.com/product/CC1021

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
AMS	AUS	AUT	Unterpremstaetten

New Fab Site

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
TSMC-WFT	T13	USA	San Jose

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 20:

MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

위한. LBL: 5A (L)TO:1750



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$12 (P) (20L) CSO: SHE (20L) CSO: SHE (21L) CCO: USA (23L) ASO: MLA

Product Affected Group:

CC1020LRSSR	CRF7964ARHBR	TRF7962ARHBR	TRF7964ARHBR
CC1020RSSR	TRF7960ARHBR	TRF7962ARHBT	TRF7964ARHBT
CC1020RSST	TRF7960ARHBT	TRF7963ARHBR	TRF7970ARHBR
CC1020WRSSR	TRF7960AY	TRF7963ARHBT	TRF7970ARHBT

CC1021RSSR CC1021RSST

Qualification Report

CC1020 family of devices: Qualification of TSMC F11 as additional wafer fab to AMS Approved: Sept 7, 2018

Product Attributes

Attributes	Qual Device: AMS PROPRIATORY DEVICE	Qual Device: CC1020	Qual Device: CC1020 AMS DEVICE
Assembly Site	ASE	Clark/Carsem*	ASE
Package Family	LQFP	QFN	QFN
Wafer Fab Supplier	TSMC FAB11	TSMC FAB11	TSMC FAB11
Wafer Process	MIXEDSIG-0.35	MIXEDSIG-0.35	MIXEDSIG-0.35

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

	Data Displayed as: Number of lots / Total sumple size / Total failed					
Туре	Test Name / Condition	Duration	Qual Device: <u>AMS</u> <u>PROPRIATORY DEVICE</u>	Qual Device: <u>CC1020</u>	Qual Device: <u>CC1020</u>	
BHAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	-		
BHAST	Biased HAST, 110C/85%RH	264 Hours	-	1/77/0	-	
ELFR	Early life Failure Rate, 125C	48 Hours	3/3000/0	-	-	
TC	Temperature Cycle, -40/125C	850 Cycles	3/231/0	-	-	
TC	Temperature Cycle, -55/125C	700 Cycles	-	1/77/0	-	
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	3/231/0	-	-	
UHAST	Unbiased HAST, 110C/85%RH	264 Hours	-	1/77/0	-	
AC	Autoclave, 121C	96 Hours		1/77/0	-	
CDM	ESD - CDM	250V	-	1/3/0	1/3/0	
НВМ	ESD - HBM	per datasheet: 1000V all pins except RF; 400V RF pins	-	-	1/3/0	
HTOL	Life Test, 125C	1000 Hours	3/231/0	1/77/0	-	
HTSL	High Temp. Storage Bake, 150C	1000 Hours	1/77/0	1/77/0	-	
LU	Latch-up	(per JESD78)	-	-	1/3/0	

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com

^{*}CC1020 QFN is qualified for both Clark and Carsem assembly. TSMC Qual vehicle was assembled in Clark.

⁻ The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours - The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours - The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles